

# NB4N11M

## 3.3 V 2.5 Gb/s Multi Level Clock/Data Input to CML Receiver/ Buffer/ Translator

### Description

The NB4N11M is a differential 1-to-2 clock/data distribution/translation chip with CML output structure, targeted for high-speed clock/data applications. The device is functionally equivalent to the EP11, LVEP11, SG11 or 7L11M devices. Device produces two identical differential output copies of clock or data signal operating up to 2.5 GHz or 2.5 Gb/s, respectively. As such, NB4N11M is ideal for SONET, GigE, Fiber Channel, Backplane and other clock/data distribution applications.

Inputs accept LVPECL, CML, LVCMOS, LVTTTL, or LVDS (See Table 5). The CML outputs are 16 mA open collector (See Figure 18) which requires resistor ( $R_L$ ) load path to  $V_{TT}$  termination voltage. The open collector CML outputs must be terminated to  $V_{TT}$  at power up. Differential outputs produces current-mode logic (CML) compatible levels when receiver loaded with 50  $\Omega$  or 25  $\Omega$  loads connected to 1.8 V, 2.5 V or 3.3 V supplies (see Figure 19). This simplifies device interface by eliminating a need for coupling capacitors.

The device is offered in a small 8-pin TSSOP package.

Application notes, models, and support documentation are available at [www.onsemi.com](http://www.onsemi.com).

### Features

- Maximum Input Clock Frequency > 2.5 GHz
- Maximum Input Data Rate > 2.5 Gb/s
- Typically 1 ps of RMS Clock Jitter
- Typically 10 ps of Data Dependent Jitter @ 2.5 Gb/s,  $R_L = 25 \Omega$
- 420 ps Typical Propagation Delay
- 150 ps Typical Rise and Fall Times
- Operating Range:  $V_{CC} = 3.0 \text{ V}$  to  $3.6 \text{ V}$  with  $V_{EE} = 0 \text{ V}$  and  $V_{TT} = 1.8 \text{ V}$  to  $3.6 \text{ V}$
- Functionally Compatible with Existing 2.5 V / 3.3 V LVDEL, LVEP, EP, and SG Devices
- These are Pb-Free Devices\*



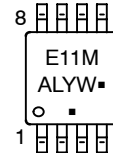
ON Semiconductor®

<http://onsemi.com>



TSSOP-8  
DT SUFFIX  
CASE 948R

### MARKING DIAGRAM\*



A = Assembly Location  
L = Wafer Lot  
Y = Year  
W = Work Week  
▪ = Pb-Free Package  
(Note: Microdot may be in either location)

\*For additional marking information, refer to Application Note AND8002/D.

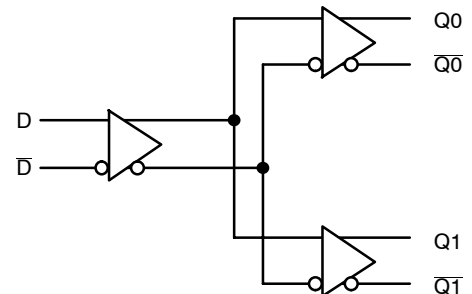


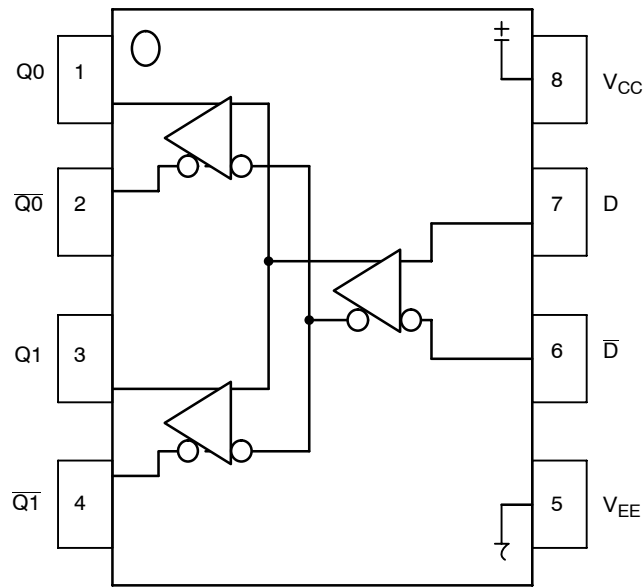
Figure 1. Functional Block Diagram

### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 10 of this data sheet.

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

# NB4N11M



**Figure 2. Pinout (Top View) and Logic Diagram**

**Table 1. Pin Description**

Pin	Name	I/O	Description
1	Q0	CML Output	Noninverted differential output. Typically receiver terminated with 50 $\Omega$ resistor to $V_{TT}$ . Open collector CML outputs must be terminated to $V_{TT}$ at powerup.
2	$\overline{Q0}$	CML Output	Inverted differential output. Typically receiver terminated with 50 $\Omega$ resistor to $V_{TT}$ . Open collector CML outputs must be terminated to $V_{TT}$ at powerup.
3	Q1	CML Output	Noninverted differential output. Typically receiver terminated with 50 $\Omega$ resistor to $V_{TT}$ . Open collector CML outputs must be terminated to $V_{TT}$ at powerup.
4	$\overline{Q1}$	CML Output	Inverted differential output. Typically receiver terminated with 50 $\Omega$ resistor to $V_{TT}$ . Open collector CML outputs must be terminated to $V_{TT}$ at powerup.
5	$V_{EE}$	-	Negative supply voltage.
6	$\overline{D}$	LVPECL, CML, HSTL, LVCMOS, LVDS, LVTTTL Input	Inverted differential input.
7	D	LVPECL, CML, HSTL, LVCMOS, LVDS, LVTTTL Input	Noninverted differential input.
8	$V_{CC}$	-	Positive supply voltage.

# NB4N11M

**Table 2. ATTRIBUTES**

Characteristics		Value
ESD Protection	Human Body Model Machine Model	> 1000 V > 70 V
Moisture Sensitivity (Note 1)	8-TSSOP	Level 1
Flammability Rating	Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in
Transistor Count		197
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test		

1. For additional information, see Application Note AND8003/D.

**Table 3. MAXIMUM RATINGS**

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V <sub>CC</sub>	Positive Power Supply	V <sub>EE</sub> = -0.5 V		4	V
V <sub>EE</sub>	Negative Power Supply	V <sub>CC</sub> = +0.5 V		-4	V
V <sub>I</sub>	Positive Input Negative Input	V <sub>EE</sub> = 0 V V <sub>CC</sub> = 0 V	V <sub>I</sub> = V <sub>CC</sub> + 0.4 V V <sub>I</sub> = V <sub>EE</sub> - 0.4 V	4 -4	V V
V <sub>O</sub>	Output Voltage Minimum Maximum			V <sub>EE</sub> + 600 V <sub>CC</sub> + 400	mV mV
T <sub>A</sub>	Operating Temperature Range			-40 to +85	°C
T <sub>stg</sub>	Storage Temperature Range			-65 to +150	°C
θ <sub>JA</sub>	Thermal Resistance (Junction-to-Ambient) (Note 2)	0 lfpm 500 lfpm	TSSOP-8 TSSOP-8	190 130	°C/W °C/W
θ <sub>JC</sub>	Thermal Resistance (Junction-to-Case)	1S2P (Note 2)	TSSOP-8	41 to 44	°C/W
T <sub>sol</sub>	Wave Solder	< 3 Sec @ 260°C		265	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

2. JEDEC standard multilayer board – 1S2P (1 signal, 2 power) with 8 filled thermal vias under exposed pad.

# NB4N11M

**Table 4. DC CHARACTERISTICS, CLOCK Inputs, CML Outputs**  $V_{CC} = 3.0\text{ V to }3.6\text{ V}$ ,  $V_{EE} = 0\text{ V}$ ,  $T_A = -40^\circ\text{C to }+85^\circ\text{C}$

Symbol	Characteristic	Min	Typ	Max	Unit
$I_{CC}$	Power Supply Current (Inputs and Outputs Open)		25	35	mA

$R_L = 50\ \Omega$ ,  $V_{TT} = 3.6\text{ V to }2.5\text{ V}$

$V_{OH}$	Output HIGH Voltage (Note 3)	$V_{TT} - 60$	$V_{TT} - 10$	$V_{TT}$	mV
$V_{OL}$	Output LOW Voltage (Note 3)	$V_{TT} - 1100$	$V_{TT} - 800$	$V_{TT} - 640$	mV
$ V_{OD} $	Differential Output Voltage Magnitude	640	780	1000	mV

$R_L = 25\ \Omega$ ,  $V_{TT} = 3.6\text{ V to }2.5\text{ V} \pm 5\%$

$V_{OH}$	Output HIGH Voltage (Note 3)	$V_{TT} - 60$	$V_{TT} - 10$	$V_{TT}$	mV
$V_{OL}$	Output LOW Voltage (Note 3)	$V_{TT} - 550$	$V_{TT} - 400$	$V_{TT} - 320$	mV
$ V_{OD} $	Differential Output Voltage Magnitude	320	390	500	mV

$R_L = 50\ \Omega$ ,  $V_{TT} = 1.8\text{ V} \pm 5\%$

$V_{OH}$	Output HIGH Voltage (Note 3)	$V_{TT} - 170$	$V_{TT} - 10$	$V_{TT}$	mV
$V_{OL}$	Output LOW Voltage (Note 3)	$V_{TT} - 1100$	$V_{TT} - 800$	$V_{TT} - 640$	mV
$ V_{OD} $	Differential Output Voltage Magnitude	570	780	1000	mV

$R_L = 25\ \Omega$ ,  $V_{TT} = 1.8\text{ V} \pm 5\%$

$V_{OH}$	Output HIGH Voltage (Note 3)	$V_{TT} - 85$	$V_{TT} - 10$	$V_{TT}$	mV
$V_{OL}$	Output LOW Voltage (Note 3)	$V_{TT} - 500$	$V_{TT} - 400$	$V_{TT} - 320$	mV
$ V_{OD} $	Differential Output Voltage Magnitude	285	390	500	mV

#### DIFFERENTIAL INPUT DRIVEN SINGLE-ENDED (Figures 14 and 16)

$V_{th}$	Input Threshold Reference Voltage Range (Note 5)	$V_{EE}$		$V_{CC}$	mV
$V_{IH}$	Single-ended Input HIGH Voltage	$V_{th} + 100$		$V_{CC} + 400$	mV
$V_{IL}$	Single-ended Input LOW Voltage	$V_{EE} - 400$		$V_{th} - 100$	mV

#### DIFFERENTIAL INPUTS DRIVEN DIFFERENTIALLY (Figures 15 and 17)

$V_{IHD}$	Differential Input HIGH Voltage	$V_{EE}$		$V_{CC} + 400$	mV
$V_{ILD}$	Differential Input LOW Voltage	$V_{EE} - 400$		$V_{CC} - 100$	mV
$V_{CMR}$	Input Common Mode Range (Differential Configuration)	$V_{EE}$		$V_{CC}$	mV
$ V_{ID} $	Differential Input Voltage Magnitude ( $ V_{IHD} - V_{ILD} $ ) (Note 7)	100		$V_{CC} - V_{EE}$	mV
$C_{IN}$	Input Capacitance (Note 7)		1.5		pF

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

- CML outputs require  $R_L$  receiver termination resistors to  $V_{TT}$  for proper operation. Outputs must be connected through  $R_L$  to  $V_{TT}$  at power up. The output parameters vary 1:1 with  $V_{TT}$ .
- Input parameters vary 1:1 with  $V_{CC}$ .
- $V_{th}$  is applied to the complementary input when operating in single-ended mode.
- $V_{CMR}$  (MIN) varies 1:1 with  $V_{EE}$ ;  $V_{CMR}$  max varies 1:1 with  $V_{CC}$ .
- Parameter guaranteed by design and evaluation but not tested in production.

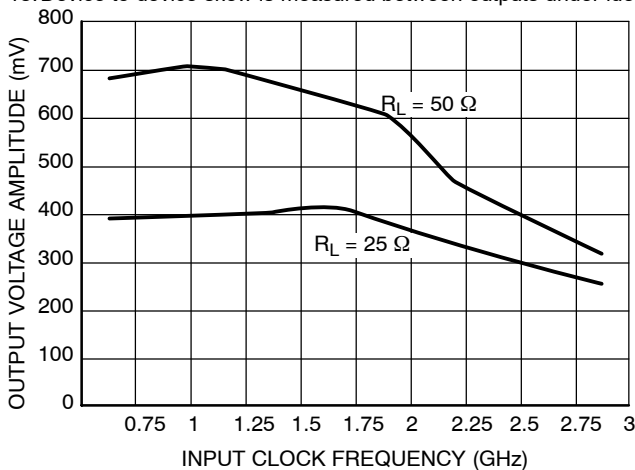
# NB4N11M

**Table 5. AC CHARACTERISTICS**  $V_{CC} = 3.0\text{ V to }3.6\text{ V}$ ,  $V_{EE} = 0\text{ V}$ ; (Note 8)

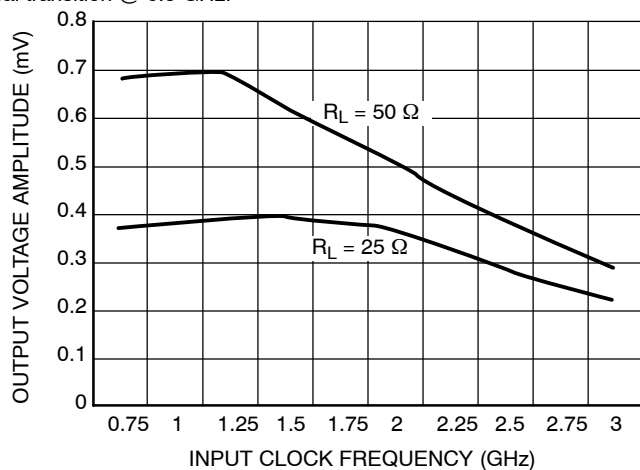
Symbol	Characteristic	-40°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$V_{OUTPP}$	Output Voltage Amplitude ( $R_L = 50\ \Omega$ ) $f_{in} \leq 1\text{ GHz}$ (See Figure 12) $f_{in} \leq 1.5\text{ GHz}$ $f_{in} \leq 2.5\text{ GHz}$	550	660		550	660		550	660		mV
$V_{OUTPP}$	Output Voltage Amplitude ( $R_L = 25\ \Omega$ ) $f_{in} \leq 1\text{ GHz}$ (See Figure 12) $f_{in} \leq 1.5\text{ GHz}$ $f_{in} \leq 2.5\text{ GHz}$	280	370		280	370		280	370		mV
$f_{DATA}$	Maximum Operating Data Rate	1.5	2.5		1.5	2.5		1.5	2.5		Gb/s
$t_{PLH}$ , $t_{PHL}$	Propagation Delay to Output Differential @ 0.5 GHz	300	420	600	300	420	600	300	420	600	ps
$t_{SKEW}$	Duty Cycle Skew (Note 9) Within Device Skew Device to Device Skew (Note 13)		2 5 20	20 25 100		2 5 20	20 25 100		2 5 20	20 25 100	ps
$t_{JITTER}$	RMS Random Clock Jitter $R_L = 50\ \Omega$ and $R_L = 25\ \Omega$ (Note 11) $f_{in} = 750\text{ MHz}$ $f_{in} = 1.5\text{ GHz}$ $f_{in} = 2.5\text{ GHz}$ Peak-to-Peak Data Dependent Jitter $R_L = 50\ \Omega$ (Note 12) $f_{DATA} = 1.5\text{ Gb/s}$ $f_{DATA} = 2.5\text{ Gb/s}$ Peak-to-Peak Data Dependent Jitter $R_L = 25\ \Omega$ (Note 12) $f_{DATA} = 1.5\text{ Gb/s}$ $f_{DATA} = 2.5\text{ Gb/s}$		1 1 1	3 3 3		1 1 1	3 3 3		1 1 1	3 3 3	ps
$V_{INPP}$	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 10)	100			100			100			mV
$t_r$ , $t_f$	Output Rise/Fall Times @ 0.5 GHz (20% – 80%)		150	300		150	300		150	300	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

8. Measured by forcing  $V_{INPP}$  (MIN) from a 50% duty cycle clock source. All output loaded with an external  $R_L = 50\ \Omega$  and  $R_L = 25\ \Omega$  to  $V_{TT}$ . Outputs must be connected through  $R_L$  to  $V_{TT}$  at power up. Input edge rates 150 ps (20% – 80%).
9. Duty cycle skew is measured between differential outputs using the deviations of the sum of  $T_{pw-}$  and  $T_{pw+}$  @ 0.5 GHz.
10.  $V_{INPP}$  (MAX) cannot exceed  $V_{CC} - V_{EE}$ . Input voltage swing is a single-ended measurement operating in differential mode.
11. Additive RMS jitter with 50% duty cycle clock signal.
12. Additive peak-to-peak data dependent jitter with input NRZ data signal (PRBS  $2^{23}-1$ ).
13. Device to device skew is measured between outputs under identical transition @ 0.5 GHz.



$(V_{CC} - V_{EE} = 3.3\text{ V } V_{TT} = 3.3\text{ V @ }25^\circ\text{C } V_{in} = 100\text{ mV})$

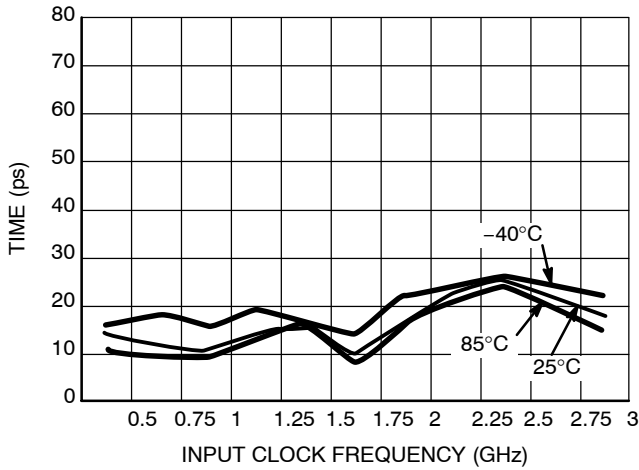


$(V_{CC} - V_{EE} = 3.0\text{ V } V_{TT} = 1.71\text{ V @ }25^\circ\text{C } V_{in} = 100\text{ mV})$

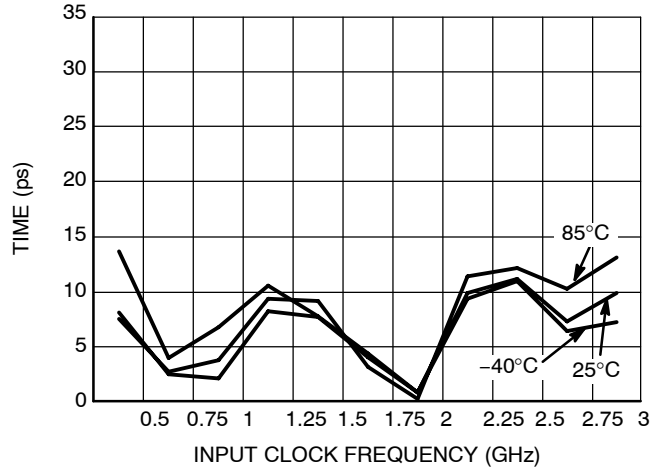
**Figure 3. Output Voltage Amplitude ( $V_{OUTPP}$ ) versus Input Clock Frequency ( $f_{IN}$ ) at Ambient Temperature (Typical)**

# NB4N11M

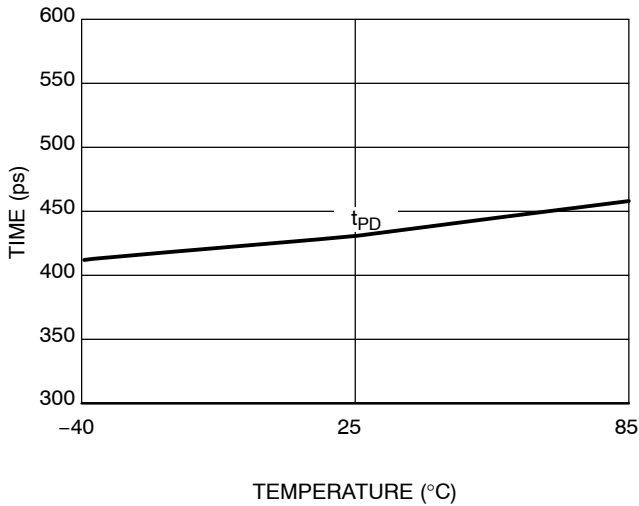
## NB4N11M



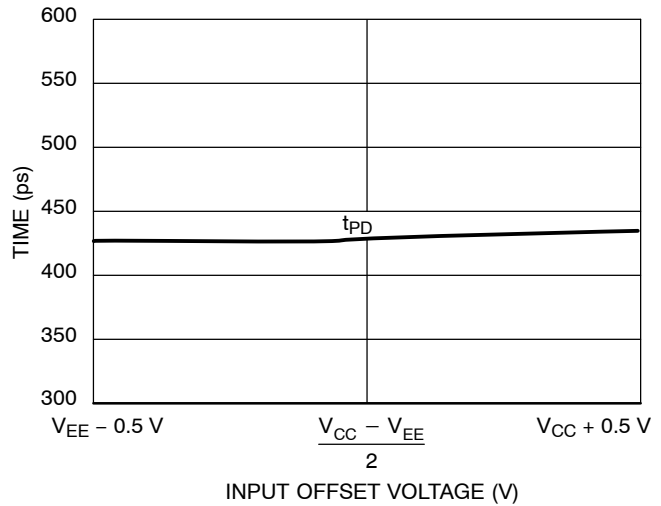
**Figure 4. Data Dependent Jitter vs. Frequency and Temperature** ( $V_{CC} - V_{EE} = 3.3\text{ V}$ ;  $V_{TT} = 3.3\text{ V}$  @  $25^\circ\text{C}$ ;  $V_{IN} = 100\text{ mV}$ ; PRBS  $2^{23}-1$ ;  $R_L = 50\ \Omega$ )



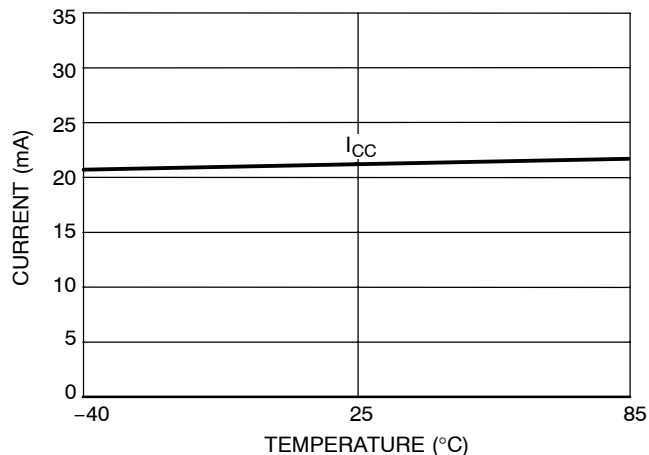
**Figure 5. Data Dependent Jitter vs. Frequency and Temperature** ( $V_{CC} - V_{EE} = 3.3\text{ V}$ ;  $V_{TT} = 3.3\text{ V}$  @  $25^\circ\text{C}$ ;  $V_{IN} = 100\text{ mV}$ ; PRBS  $2^{23}-1$ ;  $R_L = 25\ \Omega$ )



**Figure 6. Typical Propagation Delay vs. Temperature** ( $V_{CC} - V_{EE} = 3.3\text{ V}$ ;  $V_{TT} = 3.3\text{ V}$  @  $25^\circ\text{C}$ ;  $V_{in} = 100\text{ mV}$ ;  $R_L = 50\ \Omega$ )

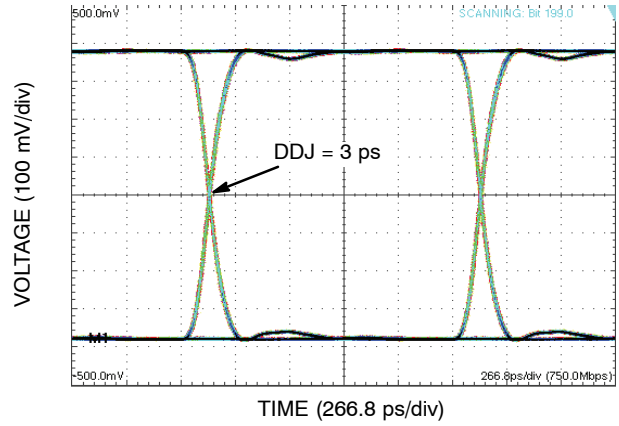
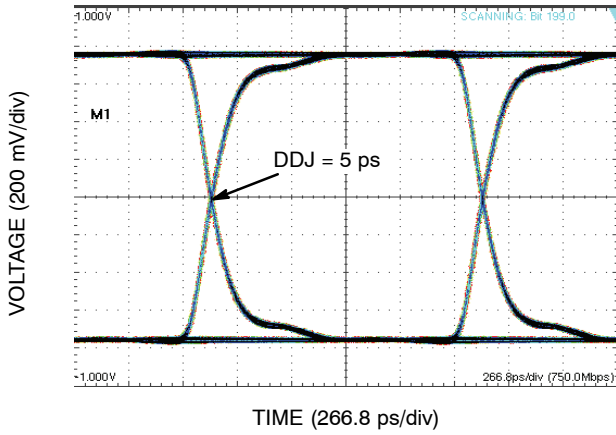


**Figure 7. Typical Propagation Delay vs. Input Offset Voltage** ( $V_{CC} - V_{EE} = 3.3\text{ V}$ ;  $V_{TT} = 3.3\text{ V}$  @  $25^\circ\text{C}$ ;  $V_{in} = 100\text{ mV}$ ;  $R_L = 50\ \Omega$ )

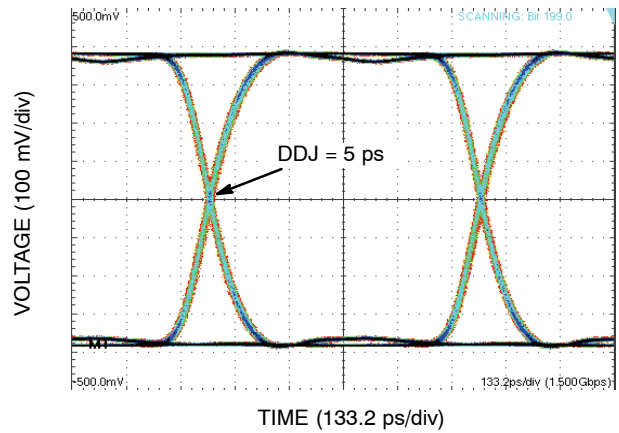
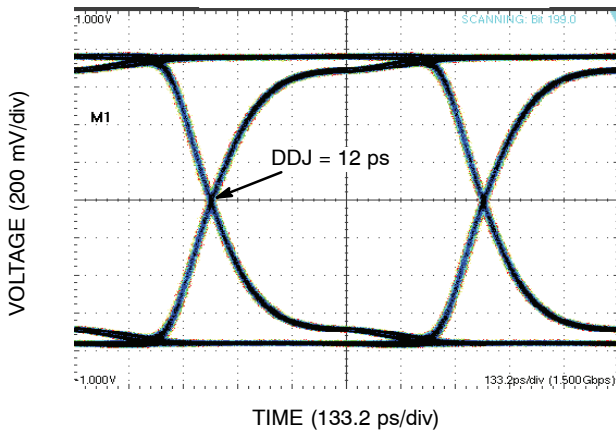


**Figure 8. Supply Current vs. Temperature**

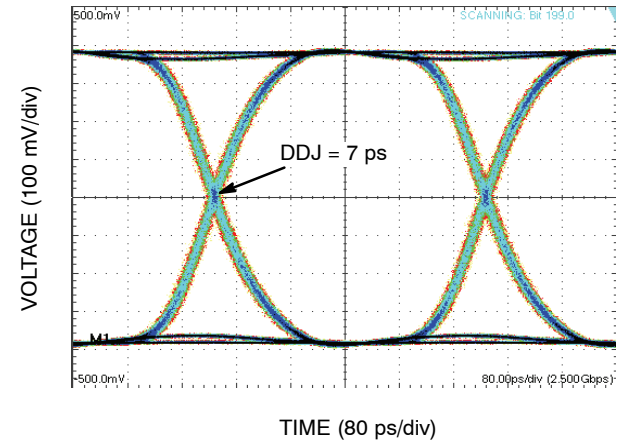
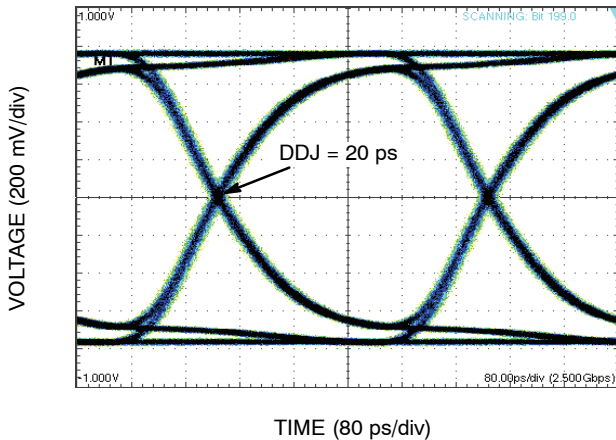
# NB4N11M



**Figure 9. Typical Differential Output Waveform at 750 Mb/s**  
 ( $R_L = 50 \Omega$  Left Plot,  $R_L = 25 \Omega$  Right Plot,  $V_{in} = 100$  mV, System DDJ = 24 ps)



**Figure 10. Typical Differential Output Waveform 1.5 Gb/s**  
 ( $R_L = 50 \Omega$  Left Plot,  $R_L = 25 \Omega$  Right Plot,  $V_{in} = 100$  mV, System DDJ = 25 ps)



**Figure 11. Typical Differential Output Waveform 2.5 Gb/s**  
 ( $R_L = 50 \Omega$  Left Plot,  $R_L = 25 \Omega$  Right Plot,  $V_{in} = 100$  mV, System DDJ = 24 ps)

# NB4N11M

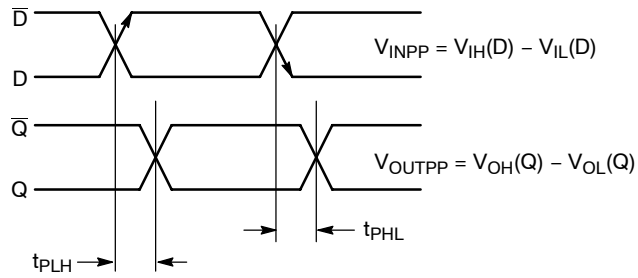


Figure 12. AC Reference Measurement

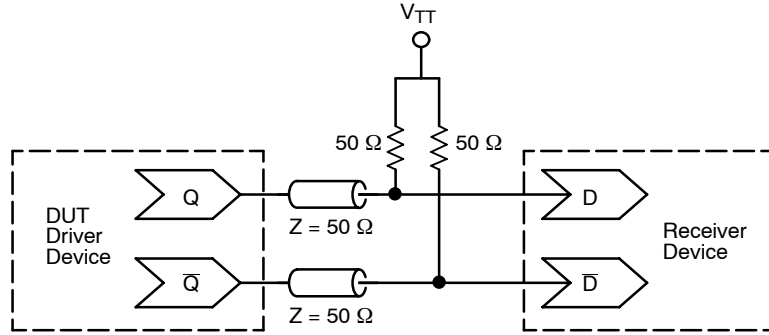


Figure 13. Typical Termination for Output Driver and Device Evaluation

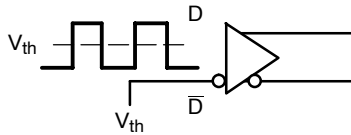


Figure 14. Differential Input Driven Single-Ended

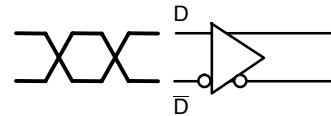


Figure 15. Differential Inputs Driven Differentially

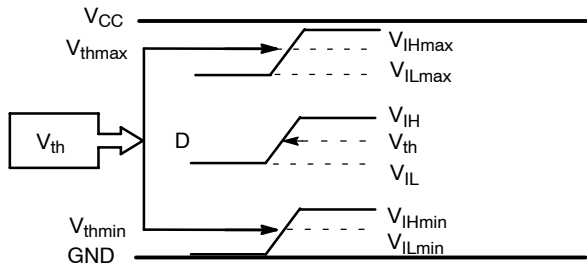


Figure 16.  $V_{th}$  Diagram

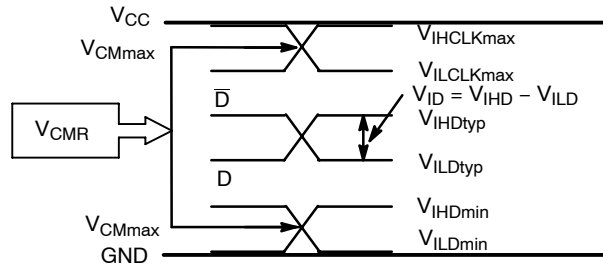


Figure 17.  $V_{CMR}$  Diagram



# NB4N11M

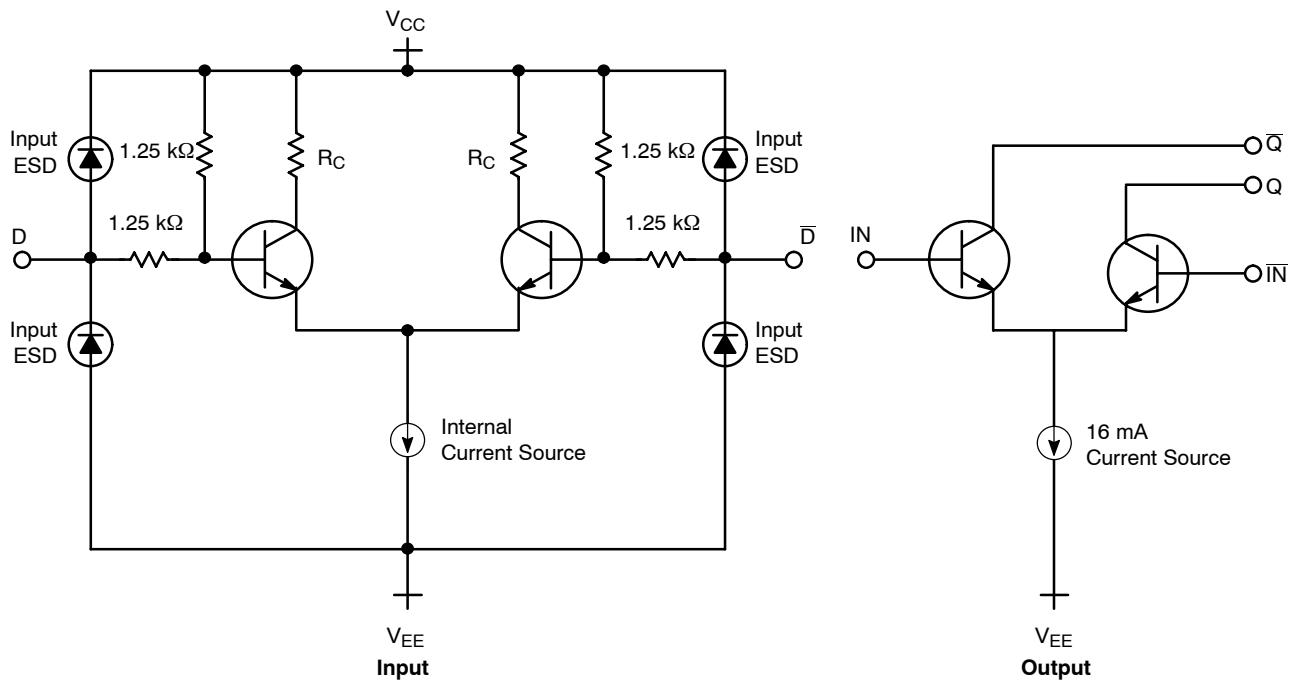


Figure 18. CML Input and Output Structure

# NB4N11M

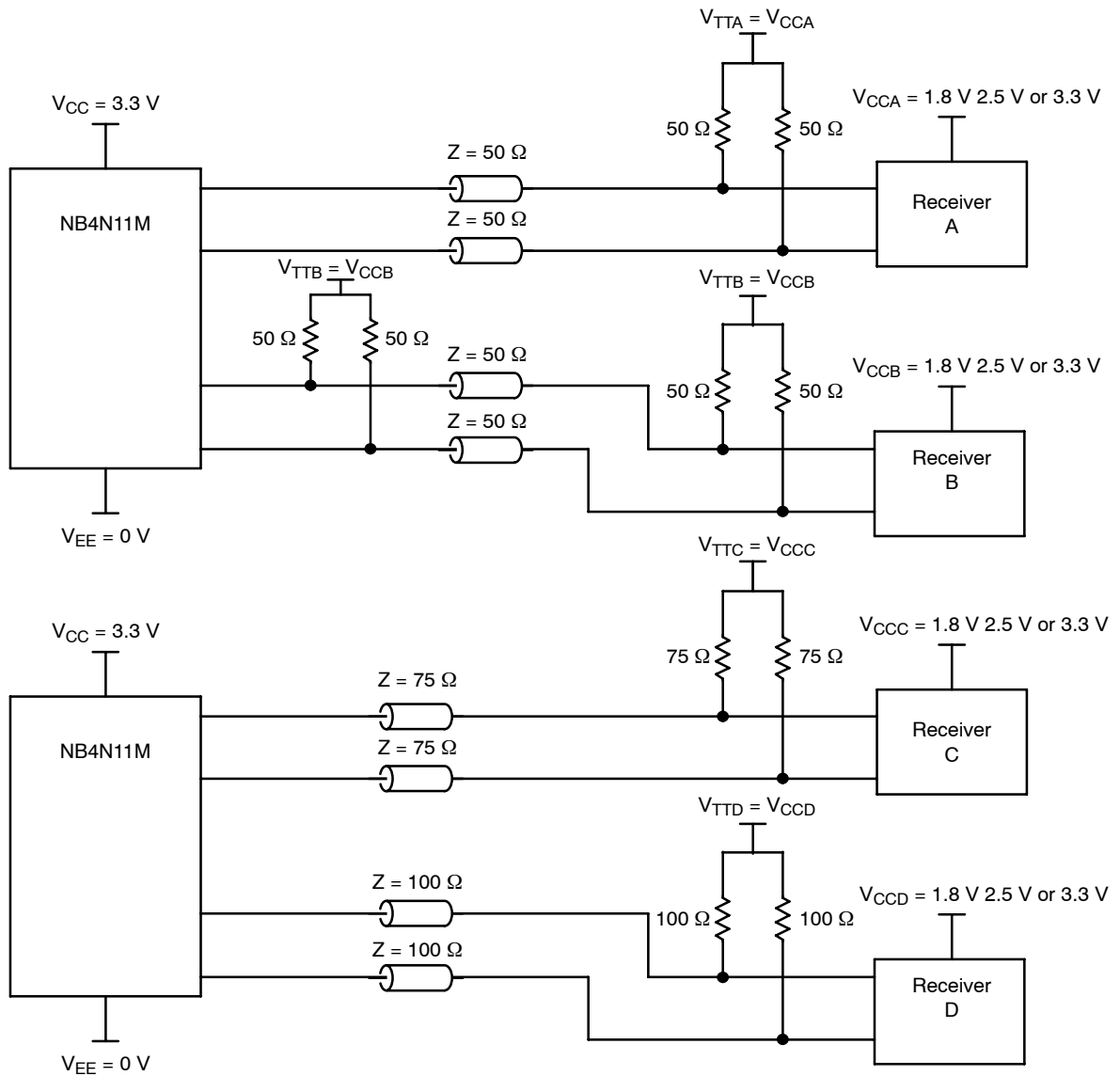


Figure 19. Typical Examples of the Application Interface

## ORDERING INFORMATION

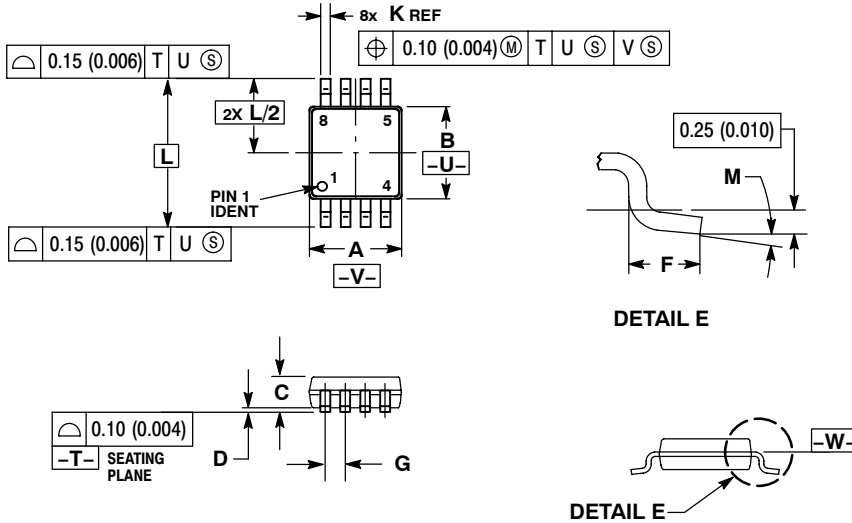
Device	Package	Shipping†
NB4N11MDTG	TSSOP-8 (Pb-Free)	100 Units / Rail
NB4N11MDTR2G	TSSOP-8 (Pb-Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# NB4N11M

## PACKAGE DIMENSIONS


### TSSOP-8 DT SUFFIX PLASTIC TSSOP PACKAGE CASE 948R-02 ISSUE A



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
  4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
  5. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
  6. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.90	3.10	0.114	0.122
B	2.90	3.10	0.114	0.122
C	0.80	1.10	0.031	0.043
D	0.05	0.15	0.002	0.006
F	0.40	0.70	0.016	0.028
G	0.65 BSC		0.026 BSC	
K	0.25	0.40	0.010	0.016
L	4.90 BSC		0.193 BSC	
M	0°	6°	0°	6°

ECLinPS is a trademark of Semiconductor Components Industries, LLC (SCILLC).

ON Semiconductor and  are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

### PUBLICATION ORDERING INFORMATION

**LITERATURE FULFILLMENT:**  
Literature Distribution Center for ON Semiconductor  
P.O. Box 61312, Phoenix, Arizona 85082-1312 USA  
**Phone:** 480-829-7710 or 800-344-3860 Toll Free USA/Canada  
**Fax:** 480-829-7709 or 800-344-3867 Toll Free USA/Canada  
**Email:** orderlit@onsemi.com

**N. American Technical Support:** 800-282-9855 Toll Free  
USA/Canada

**Japan:** ON Semiconductor, Japan Customer Focus Center  
2-9-1 Kamimeguro, Meguro-ku, Tokyo, Japan 153-0051  
**Phone:** 81-3-5773-3850

**ON Semiconductor Website:** <http://onsemi.com>

**Order Literature:** <http://www.onsemi.com/litorder>

For additional information, please contact your local Sales Representative.